

120V, 163A, $3.5m\Omega$ N-channel Power SGT MOSFET

JMSH1204PE

Features

- $\bullet \;\;$ Excellent $R_{\text{DS(ON)}}$ and Low Gate Charge
- 100% UIS Tested
- 100% ΔVds Tested
- Halogen-free; RoHS-compliant
- Pb-free plating

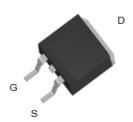
Applications

- Load Switch
- PWM Application
- Power Management

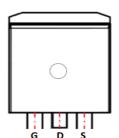
Product Summary

Parameters	Value	Unit
V_{DSS}	120	V
$V_{GS(th)_Typ}$	2.8	V
I _D (@V _{GS} =10V)	163	Α
$R_{DS(ON)_Typ}(@V_{GS}=10V$	3.5	mΩ

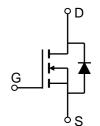




TO-263-3L Top View



Pin Assignment



Schematic Diagram

Ordering Information

	Device	Marking	MSL	Form	Package	Reel(pcs)	Per Carton (pcs)
I	JMSH1204PE	SH1204P	3	Tape&Reel	TO-263-3L	800	4000

Absolute Maximum Ratings (@ $T_C = 25$ °C unless otherwise specified)

Symbol	Parameter		Value	Unit
V_{DS}	Drain-to-Source Voltage		120	V
V_{GS}	Gate-to-Source Voltage		±20	V
I-	Continuous Drain Current	$T_C = 25^{\circ}C$	163	Λ
I _D	Continuous Diain Current	$T_C = 100$ °C	103	- A
I _{DM}	Pulsed Drain Current (1)		Refer to Fig.4	Α
E _{AS}	Single Pulsed Avalanche Energ	gy ⁽²⁾	1118	mJ
P _D	Power Dissipation	$T_C = 25^{\circ}C$	265	W
ט י		$T_C = 100$ °C	106	VV
T_{J} , T_{STG}	Junction & Storage Temperature Range		-55 to 150	°C

Thermal Characteristics

Symbol	Parameter	Max	Unit
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient ⁽³⁾	34	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.5	C/ VV



Electrical Characteristics (T_J = 25°C unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Off Cha	racteristics					
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	120	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 30V, V_{GS} = 0V$	-	-	1.0	μА
I _{GSS}	Gate-Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	±100	nA
On Cha	racteristics					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0	2.8	3.7	V
R _{DS(ON)}	Static Drain-Source ON-Resistance ⁽⁴⁾	$V_{GS} = 10V, I_D = 20A$	-	3.5	4.6	mΩ
Dynami	ic Characteristics					
R_{g}	Gate Resistance	f = 1MHz	-	2.4	-	Ω
C _{iss}	Input Capacitance	., ., ., ., .,	6922	9691	13083	pF
C _{oss}	Output Capacitance	$V_{GS} = 0V, V_{DS} = 60V,$ f = 1MHz	554	775	1047	pF
C _{rss}	Reverse Transfer Capacitance	1 - 11/11/12	19	26	35	pF
Qg	Total Gate Charge		101	141	190	nC
Q_{gs}	Gate Source Charge	$V_{GS} = 0 \text{ to } 10V$ $V_{DS} = 60V, I_{D} = 20A$	33	46	62	nC
Q_{gd}	Gate Drain("Miller") Charge	V DS = 00 V, ID = 20/1	21	30	40	nC
0 1/ 1 1						
	ing Characteristics	1			Ī	
t _{d(on)}	Turn-On DelayTime	4	-	39	-	ns
t _r	Turn-On Rise Time	$V_{GS} = 10V, V_{DD} = 60V$	-	59	-	ns
t _{d(off)}	Turn-Off DelayTime	I_{D} = 20A, R_{GEN} = 6.2 Ω	-	124	-	ns
t _f	Turn-Off Fall Time		-	62	-	ns
Body D	iode Characteristics				ı	
I _S	Maximum Continuous Body Diode Forward Current		-	-	163	А
I _{SM}	Maximum Pulsed Body Diode Forward Current		<u>-</u>	-	654	Α
V_{SD}	Body Diode Forward Voltage	$V_{GS} = 0V, I_{S} = 20A$	-		1.2	V
trr	Body Diode Reverse Recovery Time	I _F = 20A, di/dt = 100A/us	77	108	145	ns
Qrr	Body Diode Reverse Recovery Charge	$r_F = 20A$, $ui/ui = 100A/uS$	-	452.6	-	nC

Notes:

^{1.} Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

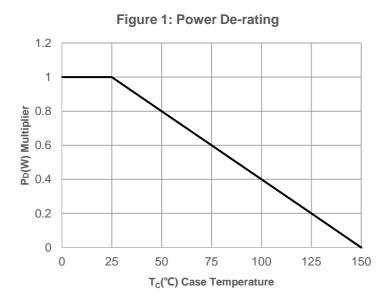
 $^{2.\;}E_{AS}\;condition:\;Starting\;T_{J}=25C,\;V_{DD}=60V,\;V_{G}=10V,\;R_{G}=25ohm,\;L=3mH,\;I_{AS}=27.3A,\;V_{DD}=0V\;during\;time\;in\;avalanche.$

 $^{3.\} R_{\theta JA}\ is\ measured\ with\ the\ device\ mounted\ on\ FR-4\ substrate\ PC\ board,\ 2oz\ copper,\ with\ minimum\ recommended\ pad\ layout.$

^{4.} Pulse Test: Pulse Width≤300µs, Duty Cycle≤0.5%.



Typical Performance Characteristics



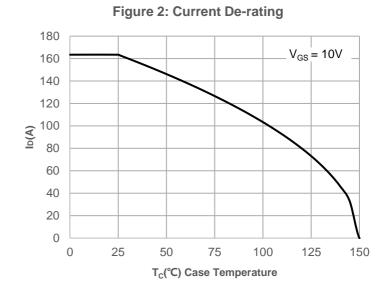
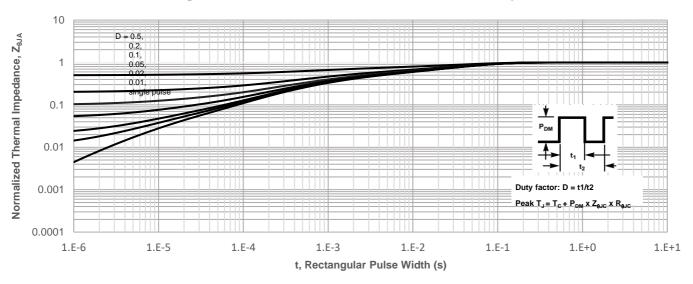
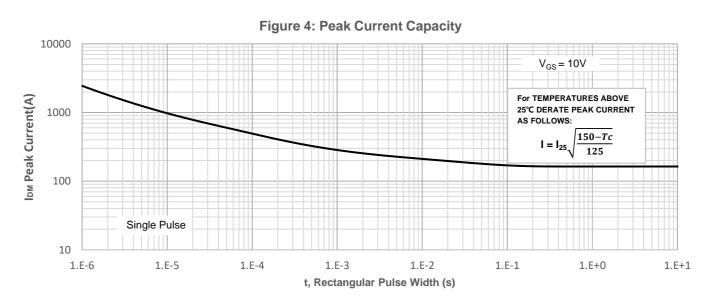


Figure 3: Normalized Maximum Transient Thermal Impedance







Typical Performance Characteristics

Figure 5: Output Characteristics

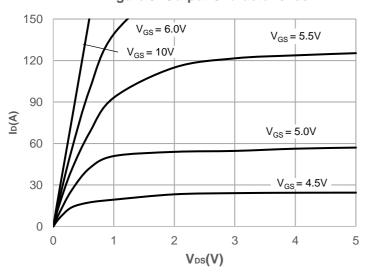


Figure 6: Typical Transfer Characteristics

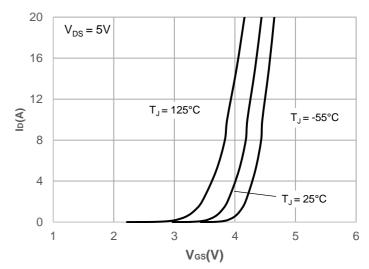


Figure 7: On-resistance vs. Drain Current

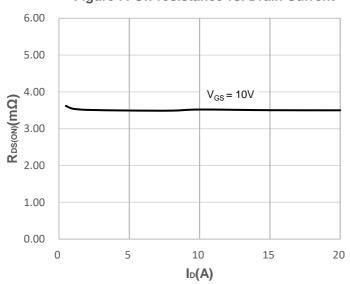


Figure 8: Body Diode Characteristics

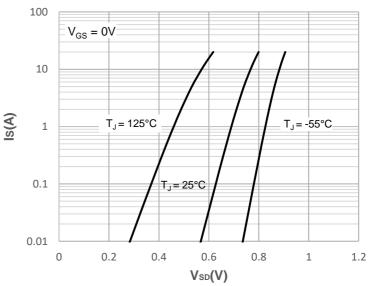


Figure 9: Gate Charge Characteristics

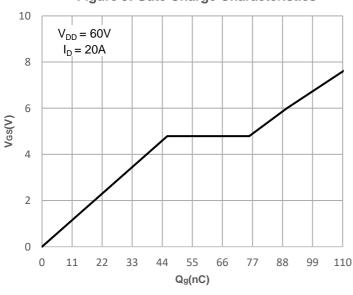
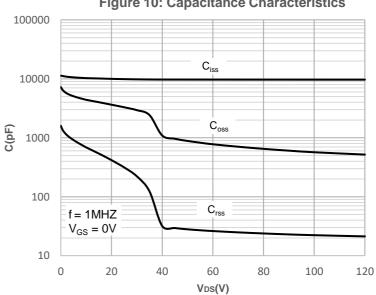


Figure 10: Capacitance Characteristics





Typical Performance Characteristics

Figure 11: Normalized Breakdown voltage vs. Junction Temperature

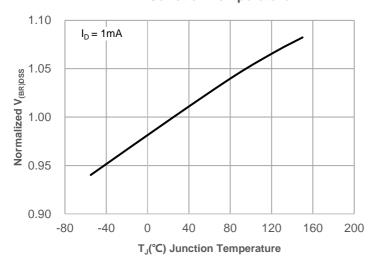


Figure 13: Normalized Threshold Voltage vs. Junction Temperature

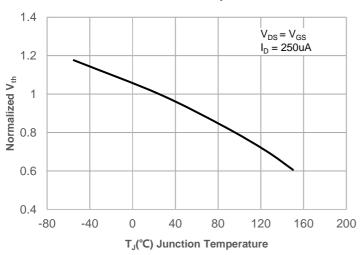


Figure 15: Maximum Safe Operating Area

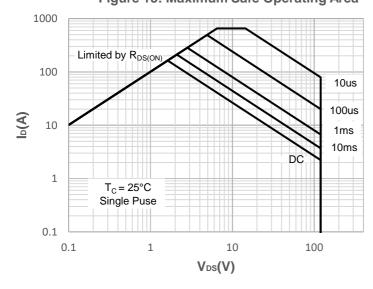
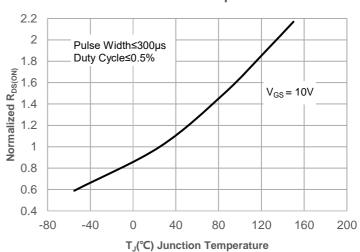
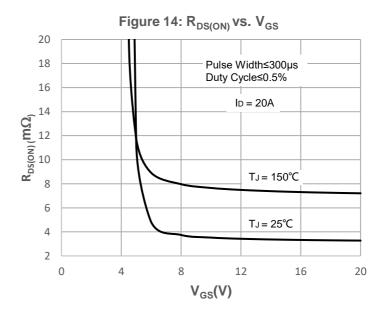


Figure 12: Normalized on Resistance vs. Junction Temperature







Test Circuit

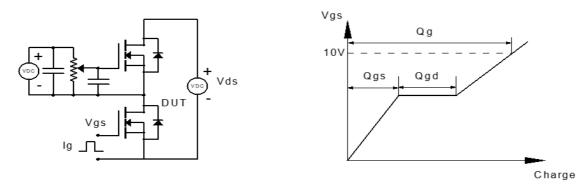


Figure 1: Gate Charge Test Circuit & Waveform

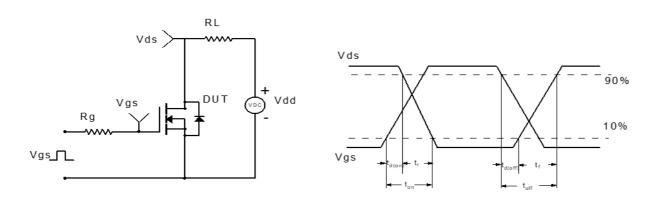


Figure 2: Resistive Switching Test Circuit & Waveform

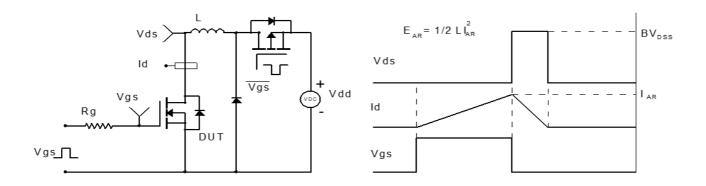


Figure 3: Unclamped Inductive Switching Test Circuit& Waveform

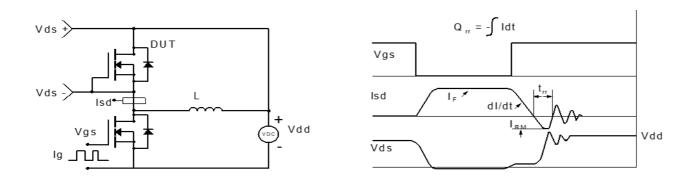
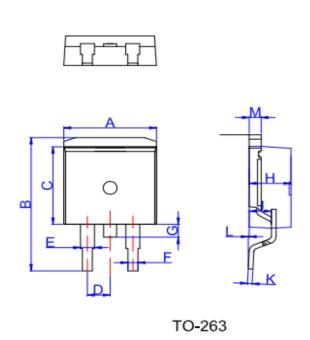


Figure 4: Diode Recovery Test Circuit & Waveform

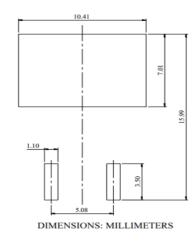


Package Mechanical Data(TO-263-3L)



			Dime	nsions		
Ref.	Millimeters			Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.
Α	9.90		10.20	0.390		0.402
В	14.70		15.80	0.579		0.622
С	9.4		9.6	0.37		0.378
D		2.54			0.100	
E	1.20		1.40	0.047		0.055
F	0.75		0.85	0.029		0.033
G			1.75			0.069
Н	4.40		4.70	0.173		0.185
J	2.30		2.70	0.091		0.106
K	0.38		0.55	0.015		0.022
L	0	0.10	0.25	0	0.004	0.010
М	1.25		1.35	0.049		0.053

Recommended Footprint



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